

RELIABILITY DATA

LT1175

8/21/2006

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF ⁽²⁾ FAILURES
SOIC/SOT/MSOP	302	9513	0443	400.15	0
	302			400.15	0

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
PLASTIC DIP	50	9603	9603	1.20	0
SOIC/SOT/MSOP	428	9615	0129	25.52	0
DD PACK	525	9638	0438	12.60	0
TO-220	350	9534	0114	9.68	0
	1,353			49.00	0

• TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	350	9616	0129	35.00	0
DD PACK	2,000	9631	0438	200.00	0
TO-220	300	9534	0122	35.00	0
	2,650			270.00	0

• THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	250	9906	0129	25.00	0
DD PACK	400	9631	0438	40.00	0
TO-220	200	9611	0114	20.00	0
	850			85.00	0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 4.60 FITS

(3) Mean Time Between Failures in Years = 24,799

Note: 1 FIT = 1 Failure in One Billion Hours.